Search Notes



Application/Control No.

10632499

Applicant(s)/Patent Under Reexamination OLSCHEWSKI, FRANK

Art Unit

Examiner

Dennis Rosario

2624

SEARCHED

GEARGIES						
Class	Subclass	Date	Examiner			
382	103	3/6/08	DR			
348	169	3/6/08	DR			

SEARCH NOTES

Search Notes	Date	Examiner
East, all dB	3/6/08	DR
ACM-+microscope +trajectory +vector-	3/6/08	DR
IEEE- ((((microscope) <in>metadata)<and>((track*)<in>metadata))<and>((vector) <in>metadata))-</in></and></in></and></in>	3/6/08	DR

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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